

Breakthrough Trench-lining Technology from Tin Model LLC

Tin Model LLC proudly announces its latest innovation: PVD trench-lining method for the semiconductor Damascene processes.

Tin Model's technology is an alternative to today's predominant method that employs specialty equipment and is expensive to operate. Tin Model's technology achieves the long-sought objectives in semiconductor manufacturing:

- 1. Reliable lining of high-aspect-ratio trenches and vias.
- 2. Uniform trench lining across large semiconductor wafers.
- 3. Symmetric coverage regardless of trench orientations (including peripheral areas).
- 4. Applicable to metals and non-metals.
- 5. Modular and compatible with cluster-tool configurations.
- 6. Scalable from current to next-generation nodes.

Tin Model's method can be used for deposition of diffusion barrier, adhesion layers and seed layers for copper interconnects. Tin Model's method is low cost in both equipment and processing.

Geometry	Type 1	Type 2	Type 2
Throw distance	20 cm	26.5 cm	32.5 cm
Cathode	Fixed planar	Fixed planar	Fixed planar
Power applied	500 watts	150 watts	150 watts
Profile on trench walls	Very good	Very good	Best
Symmetry	Excellent	Excellent	Excellent
Uniformity across wafer	Excellent	Excellent	Excellent
Coating time (for 2 nm thick wall lining)	7 minutes	12 minutes	18 minutes

*Values in the table are for a 20-cm diameter wafer, as an example.

The aim of the innovation is to increase the yield and lower the cost of manufacturing where trench lining is crucial. Tin Model's technology is patent pending and available for licensing. Please <u>contact</u> <u>us</u> for further information.